



2877

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner : Zandra V. Smith  
Group Art Unit: 2877  
Applicants : James L. Overbeck et al  
Serial No. : 09/733,162  
Filing Date : December 8, 2000  
For : OPTICAL MEASUREMENT DEVICE AND RELATED PROCESS

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

### NINTH SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Applicants wish to advise the Patent and Trademark Office of the information listed on the attached Form PTO-1449. The undersigned hereby states that no reference in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the undersigned after making reasonable inquiry, no reference in the information disclosure statement was known to any individual designated in §1.56(c) more than three (3) months prior to the filing of the information disclosure statement. The references were cited by the examiner in co-pending U.S. Patent Application Serial No. 10/236,305. A copy of each reference listed is enclosed.

Respectfully submitted,

JAMES L. OVERBECK ET AL

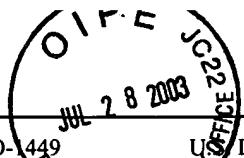
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A handwritten signature in black ink, appearing to read "Gregory P. Bondarenko".

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DISCLOSURE STATEMENT BY APPLICANT  
(Use several sheets if necessary)

ATTY. DOCKET NO. 64384.68354-002	SERIAL NO. 09/733,162
APPLICANT James L. Overbeck et al	
FILING DATE December 8, 2000	GROUP 2877

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6	0	7	5	9	4	9	06/13/2000	Hatakenaka et al			
	AB	6	1	0	6	4	5	7	08/22/2000	Perkins et al			
	AC	6	4	3	2	0	4	6	08/13/2002	Yarush et al			
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	
	AL												
	AM												
	AN												
	AO												
	AP												

## Other Citations (including Author, Title, Date, Pertinent Pages, Etc.)

	AR												
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EXAMINER DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPED 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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